

Notice of References Cited	Application/Control No. 10/525,364	Applicant(s)/Patent Under Reexamination DHAR ET AL.	
	Examiner S. Devi, Ph.D.	Art Unit 1645	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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	N	JP 200354490 A	12-2000	PCT	Nakamura et al.	Abstract
	O	WO 2005/023992	03-2005	PCT	Klimpel	
	P					
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NON-PATENT DOCUMENTS

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